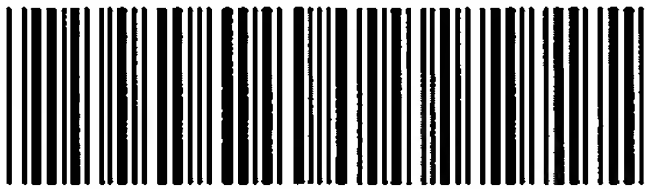


<div>Search Notes</div> <div></div>	Application No.	Applicant(s)	
	10/059,177	BEIL ET AL.	
	Examiner	Art Unit	
	John D. Lee	2874	

SEARCHED			
Class	Subclass	Date	Examiner
359	326-332	2/25/2004	JDL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
USPTO "WEST" Database searched (search strategy on separate sheet)	2/25/2004	JDL
IEEE XPlore Database searched	2/24/2004	JDL